## nexperia

## **Quarterly Reliability Monitoring Results**

Quarters: 04/2018 to 03/2019

Based on structural similarity

| Supplier   |  | User Part Number  |                                   |           |            |           |  |
|--|--|---|-----------------------------------|-----------|------------|-----------|--|
| Nexperia B.V.  |  | PBSS5130QA  |                                   |           |            |           |  |
| Name of Laboratory<br>Assembly reliability labs<br>AEC-Q101 Test |  | Part Description  |                                   |           |            |           |  |
|  |  | Nexperia DHAM Small Signal Bipolar Transistor   |                                   |           |            |           |  |
|  |  | MCD package   |                                   |           |            |           |  |
|  |  | Test Conditions   | Duration                          | # Lots    | # Quantity | # Rejects |  |
|  | <b>TEST</b><br>Pre- and Post-Stress                            |   |                                   |           |            |           |  |
| # 1  | Electrical Test  | Tamb = 25 °C  | N/A                               | see below | all parts  | see below |  |
| # 2  | <b>PC</b><br>Preconditioning                                   | JESD22-A113<br>Bake Tamb = 125 °C<br>Soak Tamb = 85 °C, RH = 85%<br>Reflow soldering          | 24 hours<br>168 hours<br>3 cycles | 156       | 12480      | 0         |  |
| # 5  | <b>HTRB</b><br>High Temperature Reverse<br>Bias                | MIL-STD-750-1<br>M1038 Method A<br>Tj = Tjmax, Vr = 100% of max. datasheet<br>reverse voltage | 1000 hours                        | 154       | 12320      | 0         |  |
| # 7  | <b>TC</b><br>Temperature Cycling                               | JESD22-A104<br>-55 °C to Tjmax, not to exceed 150°C   | 1000 cycles                       | 39        | 3120       | 0         |  |
| # 8  | <b>AC</b><br>Autoclave   | JESD22-A102<br>Tamb = 121 °C, RH = 100 %<br>Pressure = 205 kPa (29.7 psia)                    | 96 hours                          | 39        | 3120       | 0         |  |
| # 9  | <b>H3TRB</b><br>High Humidity High<br>Temperature Reverse Bias | JESD22-A101<br>Tamb = 85 °C, RH = 85%, VR > 80 % of<br>rated reverse voltage                  | 1000 hours                        | 39        | 3120       | 0         |  |
| # 10   | <b>IOL</b><br>Intermittent Operating Life                      | MIL-STD-750 Method 1037<br>ton = toff, devices powered to insure $\Delta T j =$               | 1000 hours                        | 39        | 3120       | 0         |  |
| # 20   | <b>RSH</b><br>Resistance to Solder Heat                        | JESD22-A111<br>260 °C ± 5 °C  | 10 s                              | n.a.      | n.a.       | n.a.      |  |
| # 21   | <b>SD</b><br>Solderability                                     | J-STD-002<br>Test method B and D  |                                   | 117       | 1170       | 0         |  |

## **Calculation of FIT and MTTF**

Test considered for FIT calculation: High Temperature Reverse Bias (HTRB, AEC-Q101 Test # 5) Confidence level 60%, derated to 55 °C, activation energy 0.7 eV, test time 168 to 1000 hours

| Wafer Fab Te | echnology           | Quantity | Rejects | Failure Rate (FIT) | MTTF (hrs) |
|--------------|---------------------|----------|---------|--------------------|------------|
| Nexperia Sn  | nall Signal Bipolar |          |         |                    |            |
| DHAM Tra     | ansistor            | 12320    | 0       | 0,34               | 2,90E+09   |

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